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# ON-CHIP TIME-DOMAIN METROLOGY IN SUBMICRON CMOS



Chin-Hsin Lin  
On-Chip Time-Domain  
Metrology in Submicron  
CMOS



Condition: New. Publisher/Verlag: LAP Lambert Academic Publishing | As the complexity and operational speed of today's Systems-on-Chip increase, measuring and characterizing SoC's building blocks are becoming more challenging. Embedded measuring techniques for system characterization, such as built-in self-test, are therefore becoming necessities. A Time-to-Digital Converter (TDC) is a device that has been widely used to measure the time intervals between two signal edges. The measurement resolution of a simple TDC architecture is limited by the minimum gate delay in...

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